



Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from,Europe,America and south Asia,supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts,Customers Priority,Honest Operation,and Considerate Service",our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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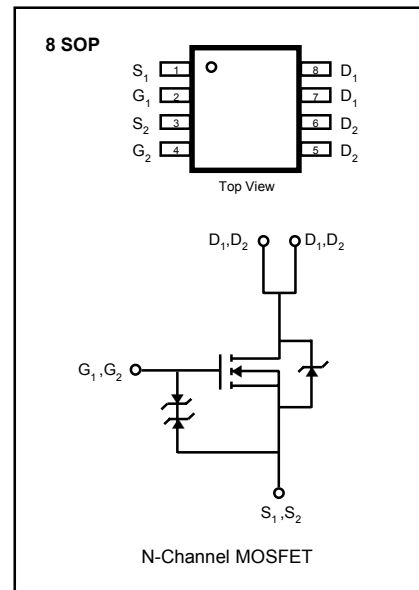
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Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China



FEATURES

- ❑ Extremely Lower $R_{DS(ON)}$
- ❑ Improved Inductive Ruggedness
- ❑ Fast Switching Times
- ❑ Rugged Polysilicon Gate Cell Structure
- ❑ Low Input Capacitance
- ❑ Extended Safe Operating Area
- ❑ Improved High Temperature Reliability
- ❑ Surface Mounting Package : **8SOP**



Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V_{DSS}	Drain-to-Source Voltage(1)	50	V
V_{DGR}	Drain-Gate Voltage($R_{GS}=1.0M\Omega$)(1)	50	V
V_{GS}	Gate-to-Source Voltage	± 20	V
I_D	Continuous Drain Current $T_A=25^\circ C$	2.0	A
I_D	Continuous Drain Current $T_A=100^\circ C$	1.6	A
I_{DM}	Drain Current-Pulsed (2)	8.0	V
P_D	Total Power Dissipation $T_A=25^\circ C$ $T_A=70^\circ C$	2.0	W
		1.3	
T_J, T_{STG}	Operating and Storage Junction Temperature Range	- 55 to +150	$^\circ C$
T_L	Maximum Lead Temp. for Soldering Purposes, 1/16" from case for 5 seconds	300	

Notes ;

(1) $T_J= 25^\circ C$ to $150^\circ C$

(2) Repetitive Rating : Pulse Width Limited by Max. Junction Temperature

Electrical Characteristics ($T_A=25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV_{DSS}	Drain-Source Breakdown Voltage	50	--	--	V	$V_{GS}=0V, I_D=250\mu A$
$V_{GS(th)}$	Gate Threshold Voltage	2.0	--	4.0	V	$V_{DS}=V_{GS}, I_D=250\mu A$
I_{GSS}	Gate-Source Leakage, Forward	--	--	1.0	μA	$V_{GS}=20V$
	Gate-Source Leakage, Reverse	--	--	-1.0	μA	$V_{GS}=-20V$
I_{DSS}	Drain-to-Source Leakage Current	--	--	2	μA	$V_{DS}=50V$
		--	--	25		$V_{DS}=40V, T_J=55^\circ\text{C}$
I_{DON}	On-State Drain-Source Current(2)	8.0	--	--	A	$V_{GS}=10V, V_{DS}=5V$
$R_{DS(on)}$	Static Drain-Source			0.3	Ω	$V_{GS}=10V, I_D=1.5A$
	On-State Resistance(2)			0.5		$V_{GS}=5.0V, I_D=0.6A$
g_{fs}	Forward Transconductance	--	2.5	--	S	$V_{DS} \geq 15V, I_D=2.0A$
$t_{d(on)}$	Turn-On Delay Time	--	--	40	ns	$V_{DD}=30V, I_D=0.6A,$ $Z_0=6.0\Omega,$
t_r	Rise Time	--	--	70		
$t_{d(off)}$	Turn-Off Delay Time	--	--	100		
t_f	Fall Time	--	--	70		
Q_g	Total Gate Charge	--	--	15	nC	$V_{DS}=25V, V_{GS}=10V,$ $I_D=1.3A$
Q_{gs}	Gate-Source Charge	--	1.0	--		
Q_{gd}	Gate-Drain ("Miller") Charge	--	2.0	--		

Thermal Resistance

Symbol	Characteristic	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient	--	62.5	$^\circ\text{C/W}$

Notes ;

- $T_J=25^\circ\text{C}$ to 150°C
- Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

Source-Drain Diode Ratings and Characteristics


Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
I_S	Continuous Source Current (Body Diode)	--	--	1.8	A	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Rectifier 
V_{SD}	Diode Forward Voltage(2)	--	--	1.2	V	$T_J=25^\circ\text{C}, I_S=1.25A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time	--	--	100	ns	$T_J=25^\circ\text{C}, I_F=2.5A, di_F/dt=100A/\mu\text{s}$

Fig 1. Output Characteristics

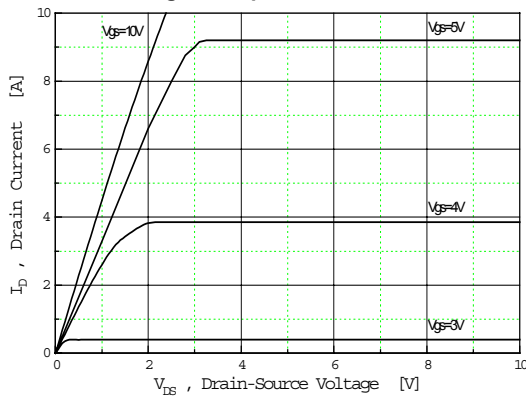


Fig 2. Transfer Characteristics

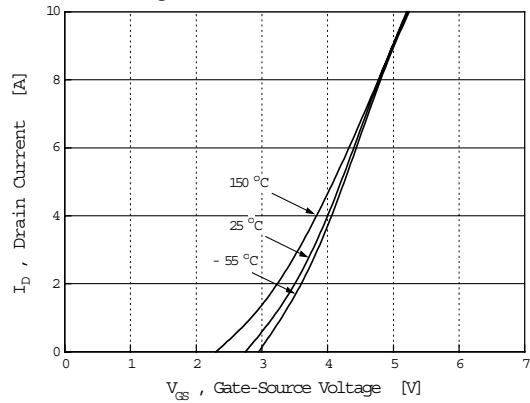


Fig 3. On-Resistance vs. Drain Current

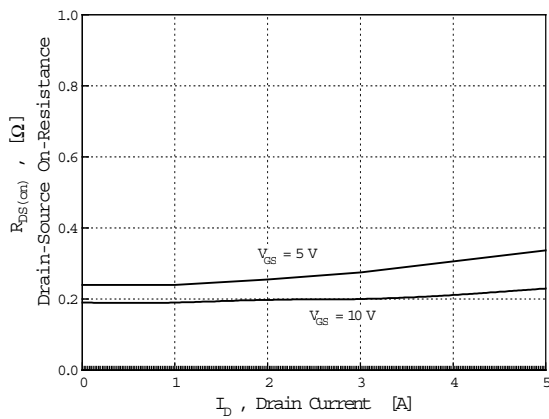


Fig 4. Capacitance vs. Drain-Source Voltage

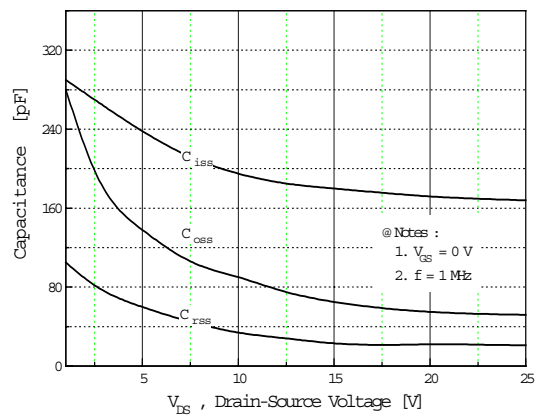


Fig 5. Breakdown Voltage vs. Temperature

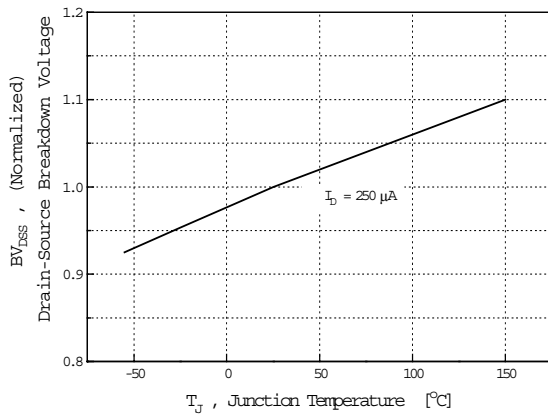


Fig 6. Normalized On-Resistance vs. Temperature

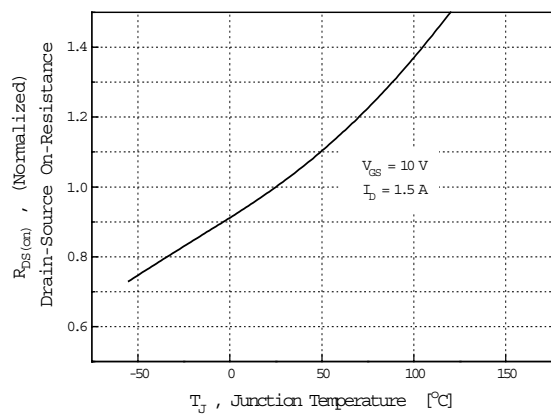


Fig 7. Normalized Effective Transient Thermal Impedance, Junction-to-Ambient

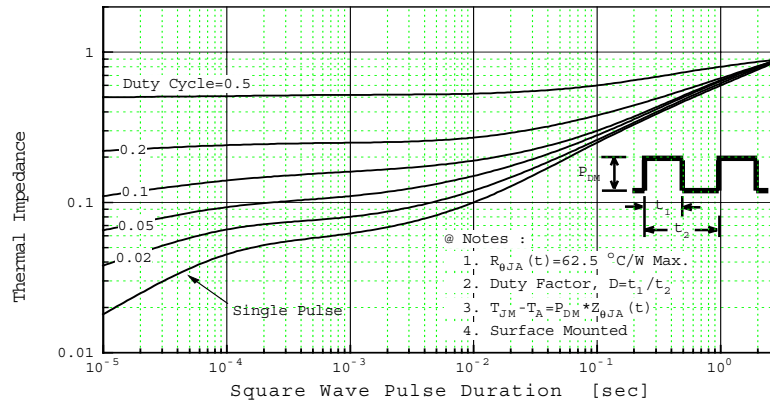


Fig 8. Source-Drain Diode Forward Voltage

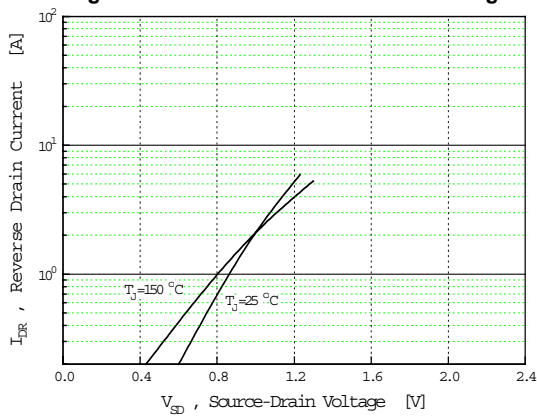


Fig 9. Gate Charge vs. Gate-Source Voltage

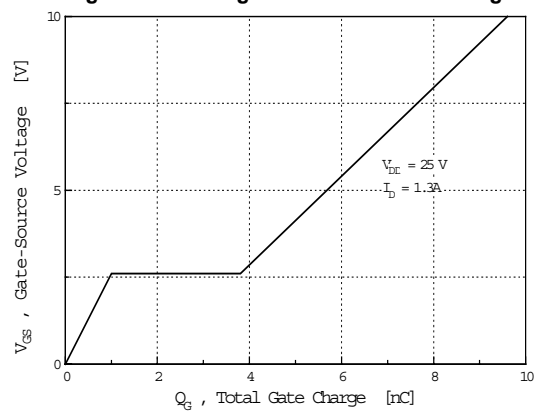
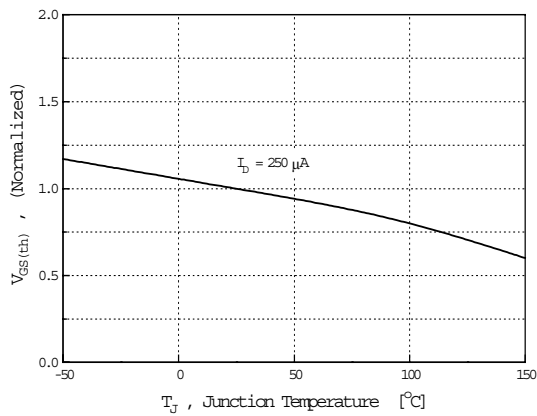


Fig 10. Threshold Voltage



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		PowerEdge™	SuperSOT™-6	

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